Searcl	h Notes
--------	---------



Application/Control No.	Applicant(s)/Patent under Reexamination	
10/608,700	MUNDT ET AL.	
Examiner	Art Unit	
Tianije Chen	2627	

	SEARCHED		
Class	Subclass	Date	Examiner
360	236		
	236.1		
•	236.2		
	236.3	5/17/2006	TJ
-			
		:	

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner

SEAR((INCLUDING SE	CH NOTES EARCH STRATEGY)
	DATE	EXMR
East Report	5/17/2006	TJ
· · · · · · · · · · · · · · · · · · ·		
<u> </u>		